Artificial Intelligence of Things Enabled Smart Applications

Guest Editors:

Prof. Dr. Maode Ma

Prof. Dr. Lu Liu

Dr. Xiaozhu Liu

Prof. Dr. Rongbo Zhu

Deadline for manuscript submissions:
closed (15 May 2022)

Message from the Guest Editors

The objective of this Special Issue is to present a collection of high-quality research papers that report the latest research advances addressing the related challenges and perspectives in the area of AIoT-enabled smart applications. Specific topics include but are not restricted to the following:

- Physical layer challenges in AIoT
- Cross-layer solutions in AIoT
- Device-to-device networks for AIoT
- Novel sensory data-acquisition techniques in AIoT
- Security, privacy, and trust in AIoT
- Computing and sensing infrastructures
- Data management in AIoT
- Sensing as a service in AIoT
- Cyber-physical systems for AIoT
- Self-learning for pattern discovery, prediction, auto-configuration in AIoT
- Smart users experience in AIoT
- AIoT-driven smart governance, smart economy, and smart environments
- AIoT-driven smart energy, smart driving, smart homes, smart living,
- AIoT-enabled COVID-19 analysis and smart health
- Deployment, test bed, experimental experiences, and innovative applications

mdpi.com/si/78701

Special Issue

Editor-in-Chief

Prof. Dr. Flavio Canavero
Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.
High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.
Journal Rank: JCR - Q2 (Physics, Applied) / CiteScore - Q1 (Electrical and Electronic Engineering)

Contact Us